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software engineering dependability

Safety and Reliability of Embedded Systems

(Sicherheit und Zuverlässigkeit eingebetteter Systeme)

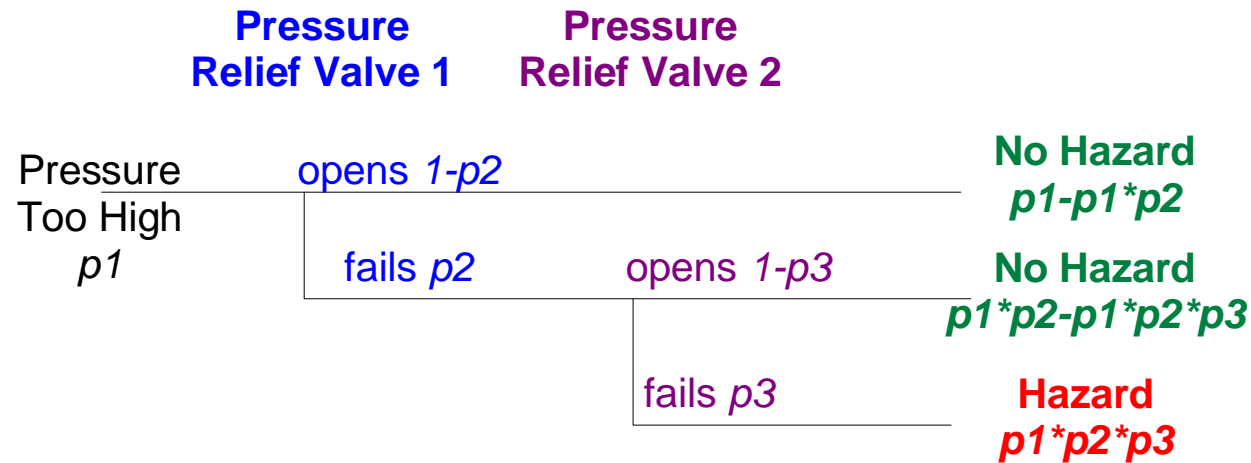
Safety and Reliability Analysis Models: Overview

- Classification
- Hazard and Operability Study (HAZOP)
- Preliminary Hazard Analysis (PHA)
- Event Tree Analysis
- Failure Modes Effects and Criticality Analysis (FMECA) (DIN 25448, IEC 812)
- Reliability Block Diagrams (IEC 61078)
- Fault Tree Analysis (DIN 25424, IEC 61025)
- Markov Analysis (IEC 61165)
 - Markov Chain
 - Markov Processes
- Petri Nets
 - Condition/Event Petri nets
 - State/Transition Petri nets
 - Predicate/Transition Petri Nets / Coloured Petri Nets
 - Timed Petri Net Types
 - SPN
 - GSPN
 - DSPN

- Focused Property
 - Safety, Reliability, Availability...
- Application Area
- Scope
 - Product / Process, HW / SW, System / Component
- Process Phase
- Search Direction
 - Inductive / Deductive
- Degree of Formality
- Representation
 - Textual, Graphical, Tabular
- Model based: Combinatorial vs. State-Based

- Hazard and Operability Study (HAZOP)
 - From chemical industry
 - Find potential hazards at early process stage
 - Check every "flow" in preliminary design scheme for deviations
 - Manual search using guide-words (more, less, no, reverse...)
- Preliminary Hazard Analysis (PHA)
 - During requirements analysis or early design phase
 - Coarse identification, classification and counter-measures for potential hazards
 - Table representations

- Forward-searching technique with graphical representation
- Search consequences to given hazard, depending on conditions



- The Failure Mode, Effects and Criticality Analysis (FMECA) is a preventive method for the identification of problems, their risks and effects
- FMECA has the following goals
 - Detection of hazards and problems
 - Identification of potential risk
 - Quantification of risks
 - Determination of corrective measures
- FMECA can be performed as **component FMECA** (e.g. for a subsystem), as **system FMECA** (a complete system) or as **process FMECA** (e.g. for a development process)

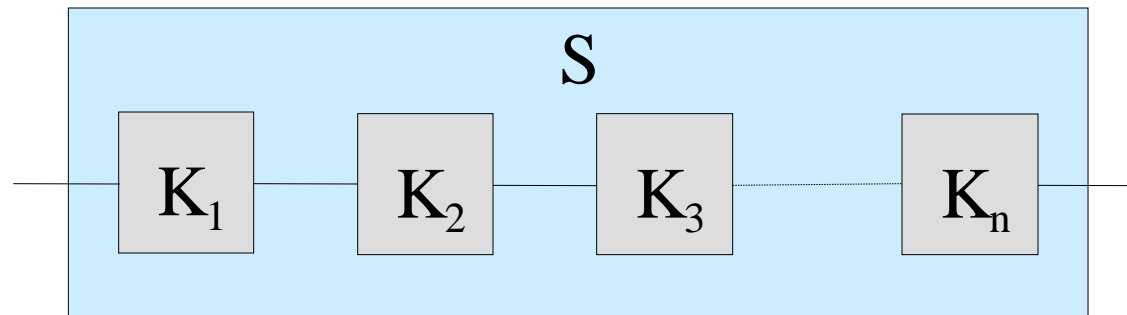
- FMECA is done in the following steps
 - Fault analysis: Collection of possible faults including available information about the type, causes and consequences
 - Risk evaluation with the aid of the risk priority number

$$\text{RPN} = \text{occurrence probability} * \text{severity of consequences} * \text{probability of non-detection}$$

- If for the three influencing factors a value between 1 and 10 is used (1= no risk, minor occurrence; 10 = high risk, high occurrence), the RPN is a value between 1 and 1000
- The risk priority number generates a ranking for the causes of faults
- Causes of faults with a high risk priority number are to be handled with priority

- Interconnection of all components of a system which are involved in performing the required function; represented as a flow chart
- RBDs distinguish only two states (intact/failed)
- Reliability function $R(t)$
 - $F(t)$ gives the probability that at time t at least one failure has occurred; thus $R(t) = 1 - F(t)$ is the probability that at time t no failure has occurred yet

- n serial connected components K_i . The system S fails if one of the components fails



$$R_S(t) = R_{K_1}(t) R_{K_2}(t) R_{K_3}(t) \dots R_{K_n}(t) = \prod_{i=1}^n R_{K_i}(t)$$

- Example:
Two components with $R_1 = R_2 = 0,8$: $R_S = 0,64$

Reliability Block Diagrams

Parallel Connection

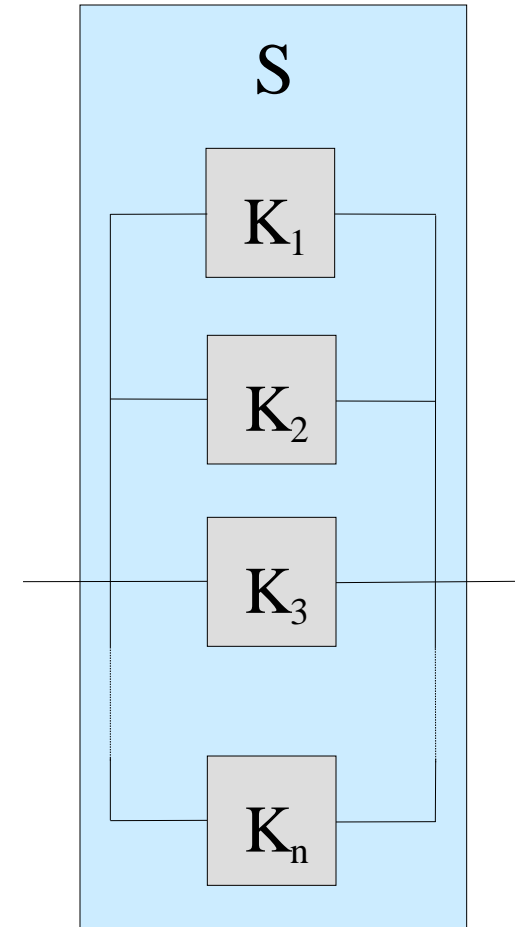
- n parallel connected components K_i . The system S fails if all components fail

$$F_S(t) = F_{K_1}(t) F_{K_2}(t) F_{K_3}(t) \dots F_{K_n}(t) = \prod_{i=1}^n F_{K_i}(t)$$

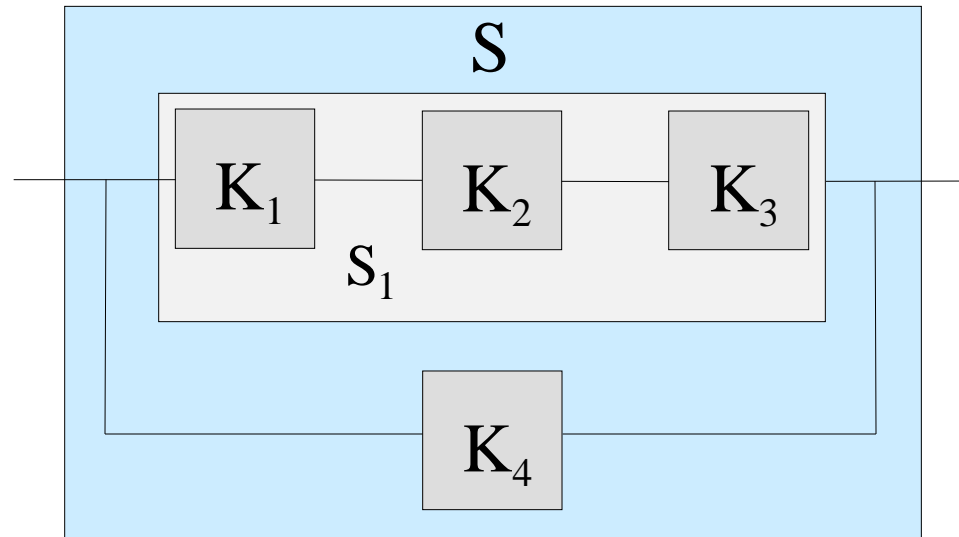
$$R_S(t) = 1 - F_S(t) = 1 - \prod_{i=1}^n F_{K_i}(t) = 1 - \prod_{i=1}^n (1 - R_{K_i}(t))$$

- Example:

Two components with $R_1 = R_2 = 0,8$: $R_S = 0,96$



- Combinations of serial and parallel connections can be solved hierarchically



- Example:

System S is a parallel connection of the subsystem S_1 with component K_4

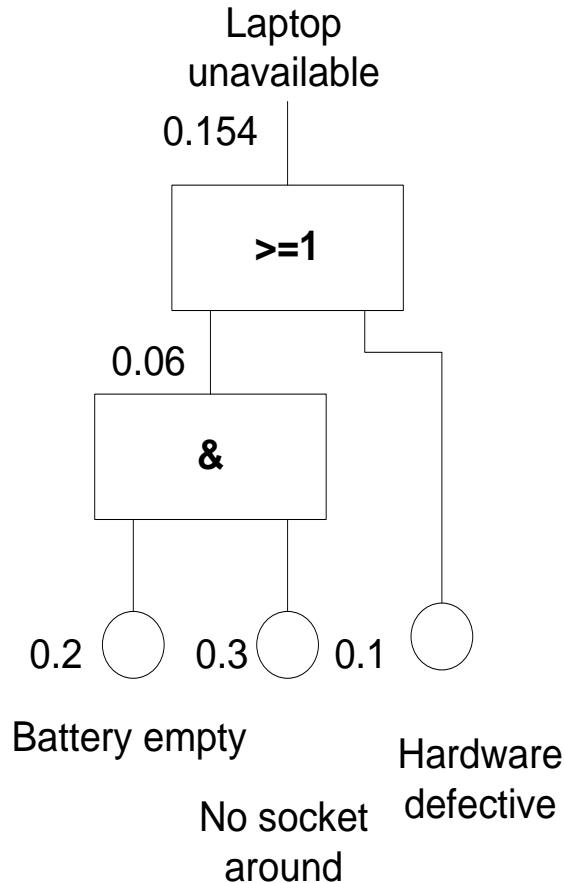
The reliability of the subsystem S_1 is:

$$R_{S_1}(t) = R_{K_1}(t) R_{K_2}(t) R_{K_3}(t)$$

The reliability of the system S is:

$$\begin{aligned} R_S(t) &= 1 - [(1 - R_{K_4}(t)) (1 - R_{S_1}(t))] \\ &= 1 - [(1 - R_{K_4}(t)) (1 - R_{K_1}(t) R_{K_2}(t) R_{K_3}(t))] \end{aligned}$$

All components have the reliability $R = 0,8$: $R_S = 0,9024$

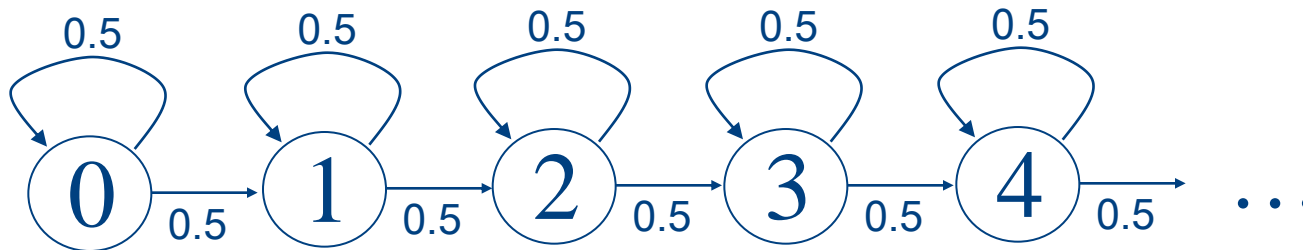


- Analysis method for the qualitative and quantitative evaluation of a *specific* failure of a system
- Deductive (backward searching)
- Graphical and intuitive technique
- Based on Boolean logic and combinatorics
- Widely accepted, captured in standards / handbooks
- Has been used and extended since 1961

- Markov Analysis
 - Markov Chain
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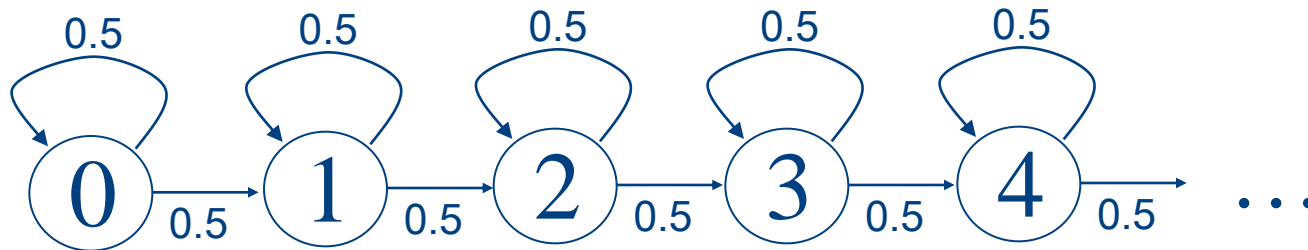
- Markov models are based on a description of the system behavior with state machines
- Common assumption of all Markov Models:
The probability of the next state depends on the current state; it is independent from previous states, i.e. Markov models do not take into account the history
- Various Model types, e.g.:
 - Discrete time models (Markov chain)
 - Continuous time models; also called Markov processes

- Markov chains assume that state changes occur at discrete points in time
- Example: Throwing a coin n times and counting the results where we got the “front side” as the result of this experiment
- Obviously this can be modeled with the following Markov chain:

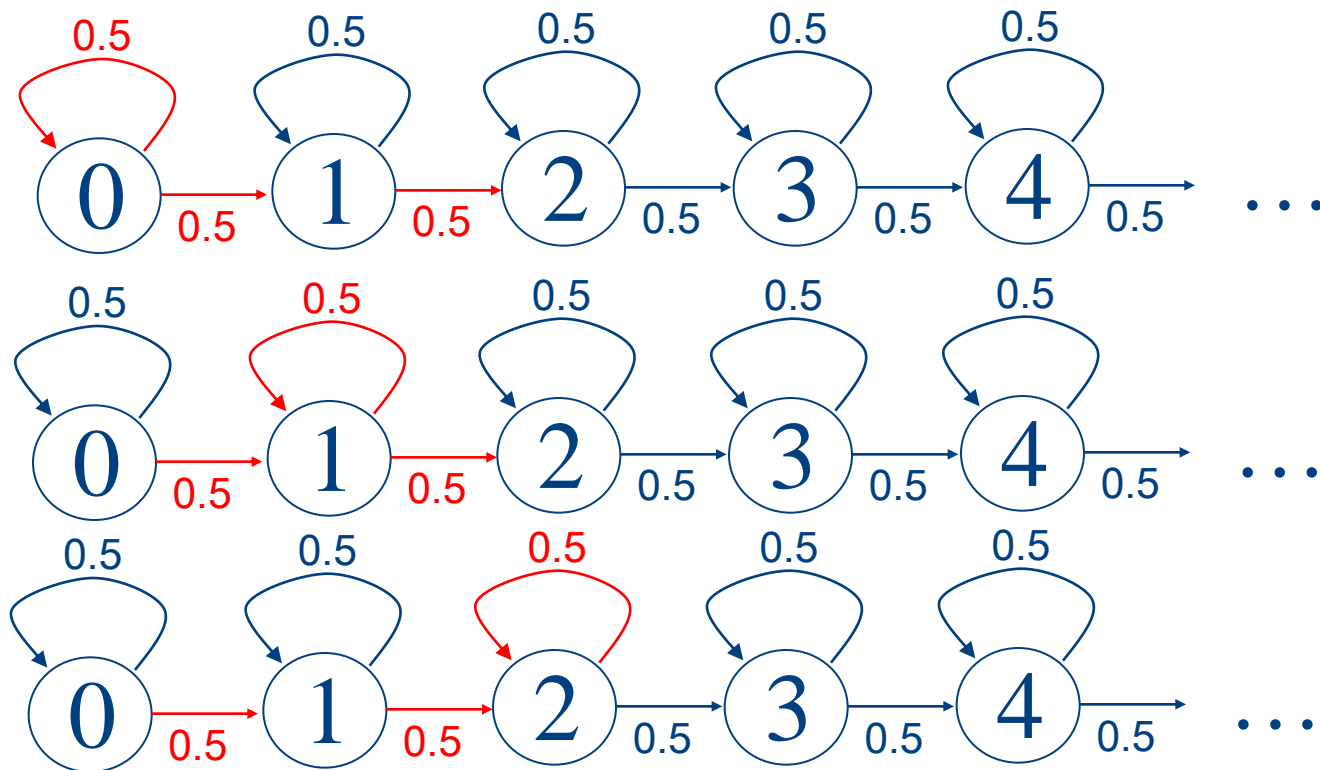


- If the current state is i then the probabilities to stay at state i or to enter state $(i+1)$ are both 0.5 . A state change may only occur at the discrete point in time, when the coin is thrown.

- What is the probability for 2 “front sides” after throwing the coin twice?
- Answer: There is one path of length 2, that leads into state 2, associated with probability $(0.5 * 0.5) = 0.25$

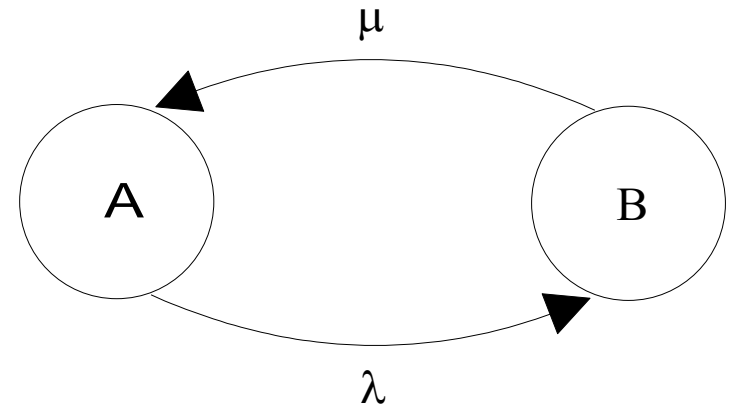


- What is the probability for 2 “front sides” after throwing the coin three times?
- Answer: There are the following paths of length 3, that lead into state 2



- Each of the three paths has probability $(0.5 * 0.5 * 0.5) = 0.125$
- The probability for 2 “front sides” after throwing the coin three times is $3 * 0.125 = 0.375$

- Markov processes are continuous time models
- Example
 - A system with failure rate λ and repair rate μ is to be analyzed with the aid of a Markov model. The Markov model has the states A and B
 - A is the state where the system is intact. B is the state where the system failed
 - The system changes with the failure rate λ from the intact state into the failed state. With the repair rate μ it changes from the failed state into the intact operation



$$\frac{dP_A(t)}{dt} = -\lambda P_A(t) + \mu P_B(t)$$

$$\frac{dP_B(t)}{dt} = \lambda P_A(t) - \mu P_B(t) = -\frac{dP_A(t)}{dt}$$

$$P_A(t) + P_B(t) = 1$$

$$P_A(t) = \frac{\mu}{\mu + \lambda} + \left(c - \frac{\mu}{\mu + \lambda}\right) e^{-(\mu + \lambda)t}$$

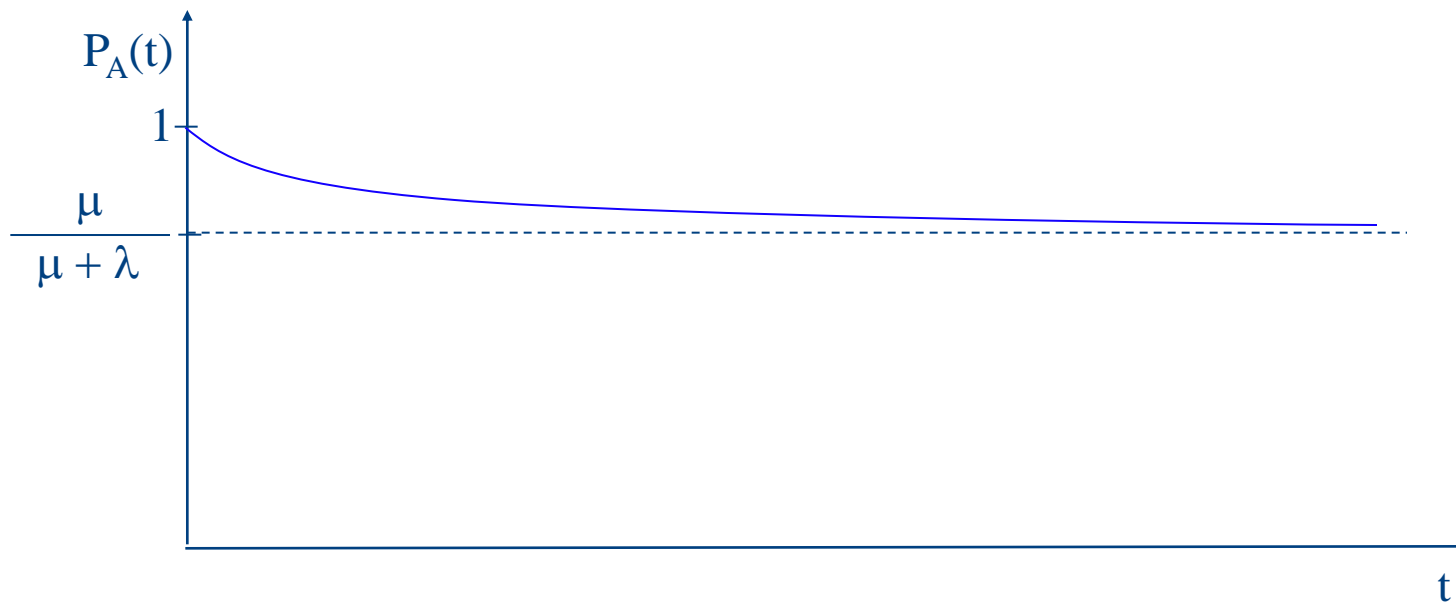
$$P_B(t) = 1 - P_A(t) = 1 - \left[\frac{\mu}{\mu + \lambda} + \left(c - \frac{\mu}{\mu + \lambda}\right) e^{-(\mu + \lambda)t}\right]$$

- For t towards infinite one gets the steady state of the system

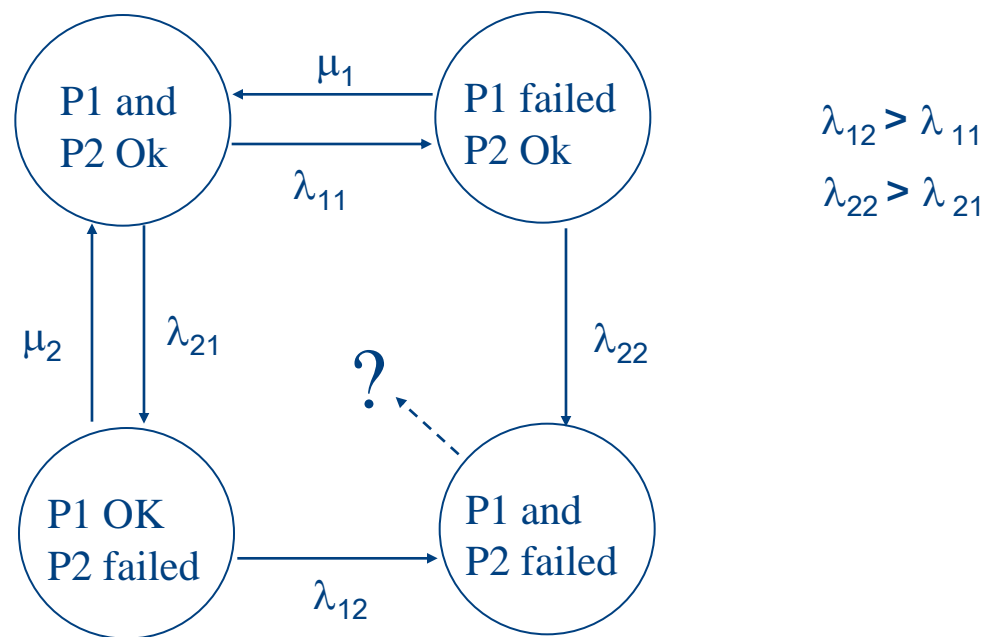
$$\lim_{t \rightarrow \infty} P_A(t) = \frac{\mu}{\mu + \lambda}$$

$$\lim_{t \rightarrow \infty} P_B(t) = 1 - \frac{\mu}{\mu + \lambda}$$

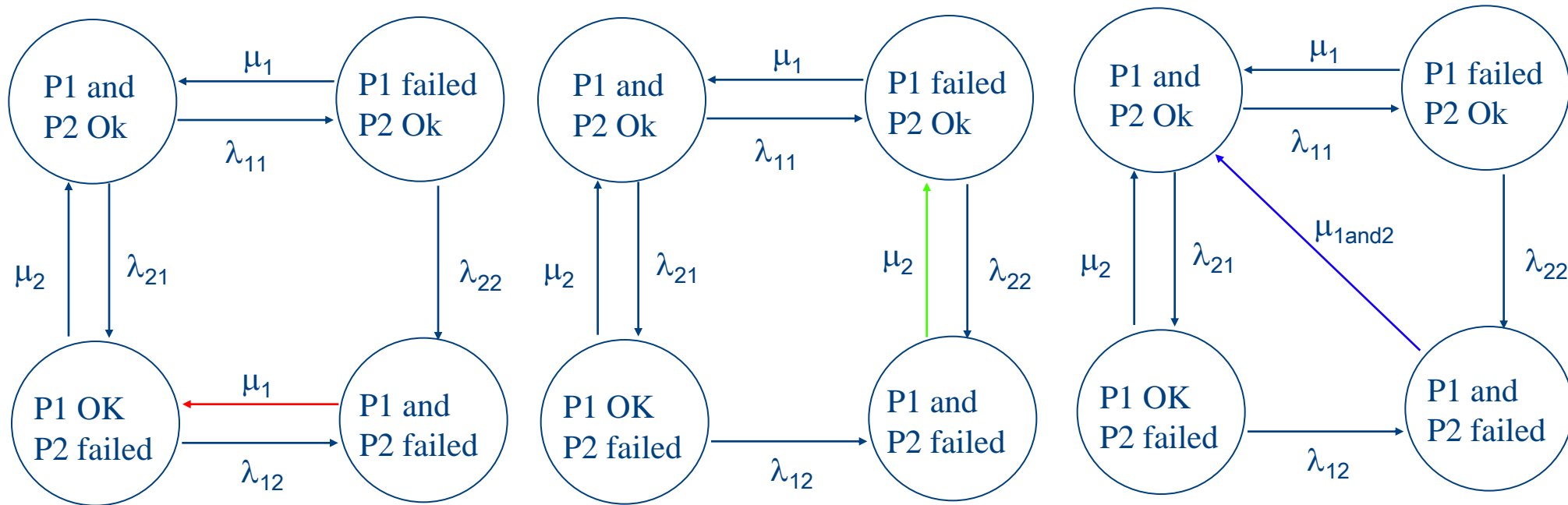
- If the repair rate is high compared to the failure rate the probability that the system is intact approaches 1
- If the repair rate is low compared to the failure rate the probability that the system is intact approaches zero



- Let's assume we have to model a system that uses two pumps to pump water to a higher level. In normal operating mode each pump runs at 50% of its maximum power. The remaining pumps takes over the complete load, if one pump fails and thus gets additional stress, which increases its failure probability. How could that be modeled?



- Alternative repair strategies when both pumps have failed:
 - Repair P1 then switch on again,
 - Repair P2 then switch on again,
 - Repair P1 and P2 and then switch on again.



- Petri Nets
 - Condition/Event Petri nets
 - State/Transition Petri nets
 - Predicate/Transition Petri Nets / Coloured Petri Nets
 - Timed Petri Net Types
 - SPN
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- The concept of Petri nets has its origin in Carl Adam Petri's dissertation *Kommunikation mit Automaten*, submitted in 1962 to the faculty of Mathematics and Physics at the Technische Universität Darmstadt, Germany
- Various Petri net types, e.g.:
 - Condition/Event Petri nets
 - State/Transition Petri nets
 - Predicate/Transition Petri Nets / Coloured Petri Nets
 - Timed Petri Net Types
 - Stochastic delay
 - No delay
 - Deterministic delay

A Petri Net N contains at least *places* (P), *transitions* (T) and a *flow relation* (F) as well as an initial marking (M_0): $N = (P, T, F, M_0)$:

- $P \cap T = \emptyset$
- $F \subseteq (P \times T) \cup (T \times P)$
- $M_0: P \rightarrow \mathbb{N}_0$

- State elements hold either one or no token
 - state elements represent conditions, which can be true or false
 - transition elements are represent local events
- Event is enabled if and only if
 - all its pre-conditions (connected by incoming arcs) are true
 - all its post-conditions (connected by outgoing arcs) are false
- An event occurrence negates its pre- and post-conditions
- Events with overlapping pre-conditions are in conflict
- Events with overlapping post-conditions are in contact

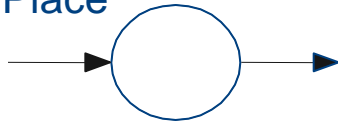
- **Petri nets**

- Directed graph, which consists of two different **kinds** of nodes:
 - **Places** and **Transitions**

Places

represent a clipboard of information

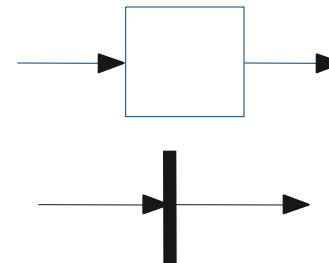
Place



Transitions

describe the processing of information

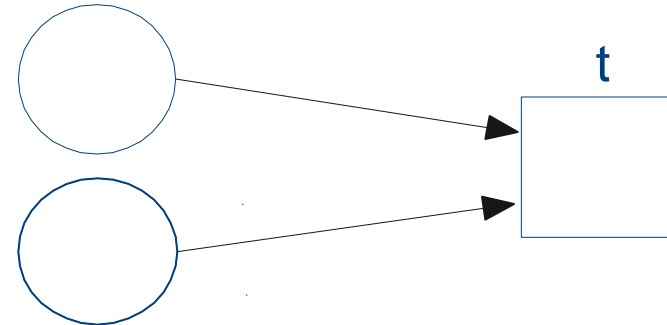
Transition



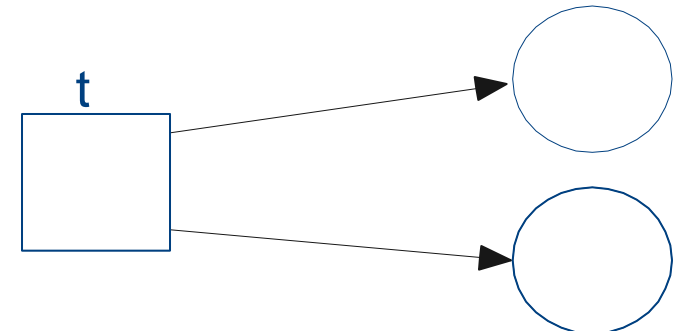
- Semantic

- **Arcs** are only allowed between a node and the other kind of node.
- **Places** from which arcs run to a transition t are called **Input Places** of t
- **Places** to which arcs run from a transition t are called **Output Places** of t .

Input places of t



Output places of t

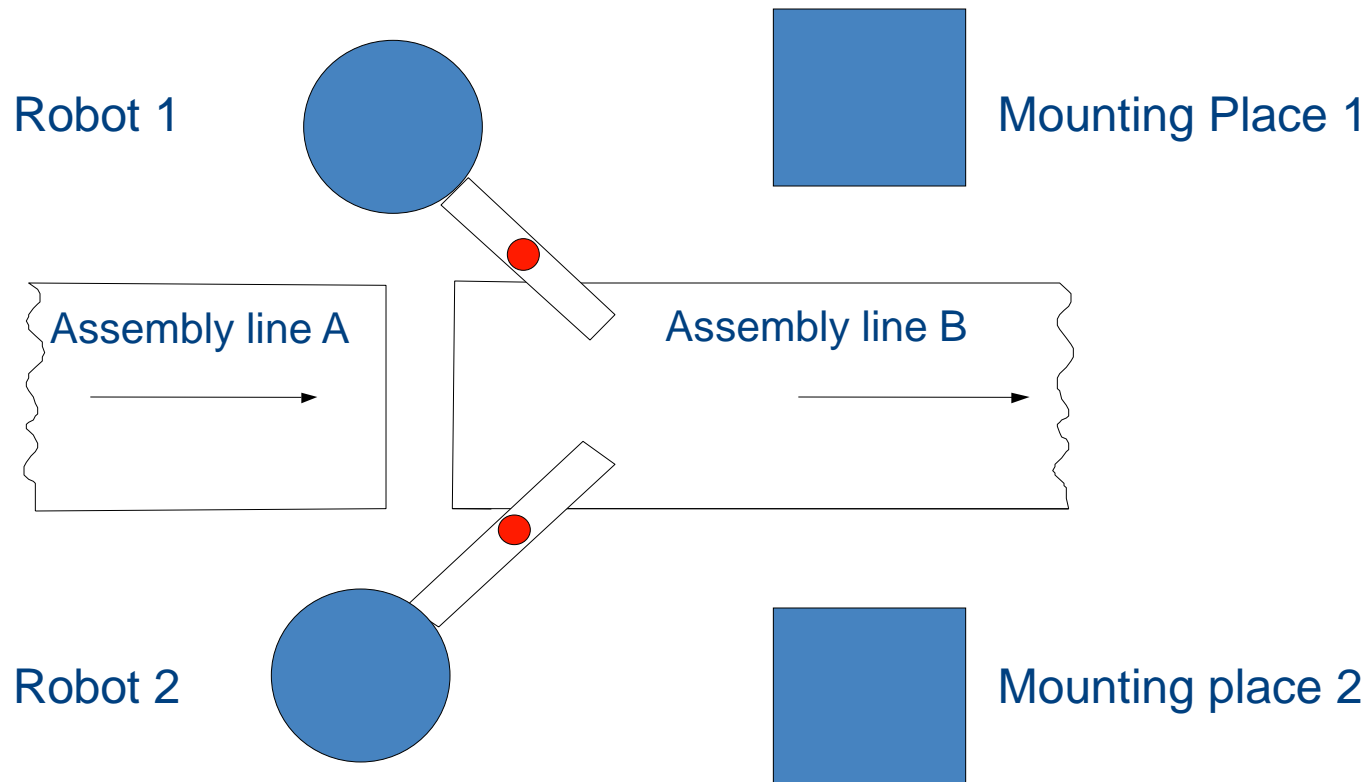


- **C/E Net**

- Objects, respectively tokens, are of **Boolean** data type
- Transitions are interpreted as **Events**
- Places are denoted as **Conditions**
- Each place is allowed to receive exactly one or no token.
- Additional firing condition:

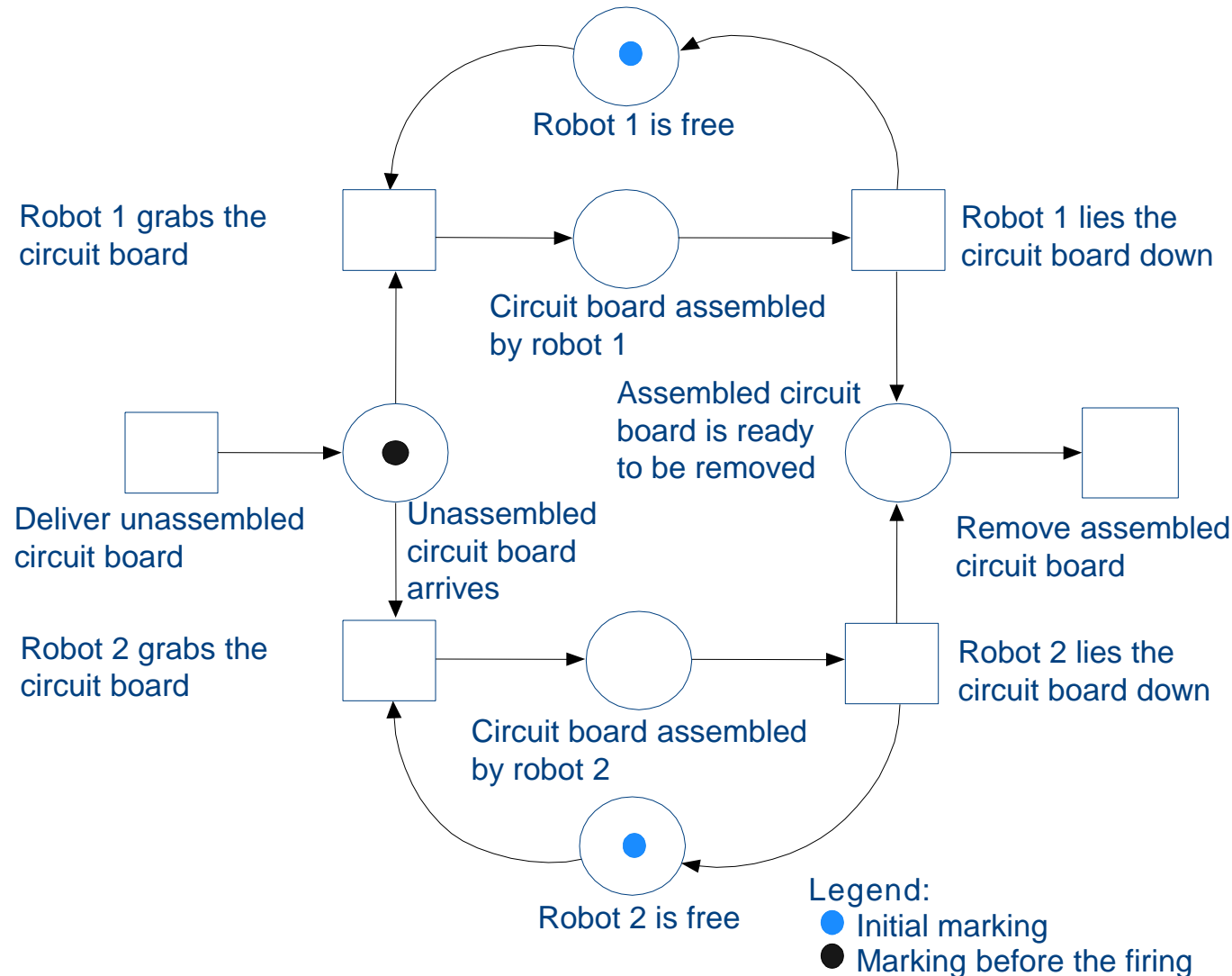
C A transition t can fire if each input space of t contains one token and if each output space of t is empty. When it fires, the token in each input space will be consumed respectively. One token will be assigned to each output space.

- Example
 - 2 Robots assemble circuit boards with electronic devices, which are delivered on an assembly line A.



- C/E Net of the assembling robot

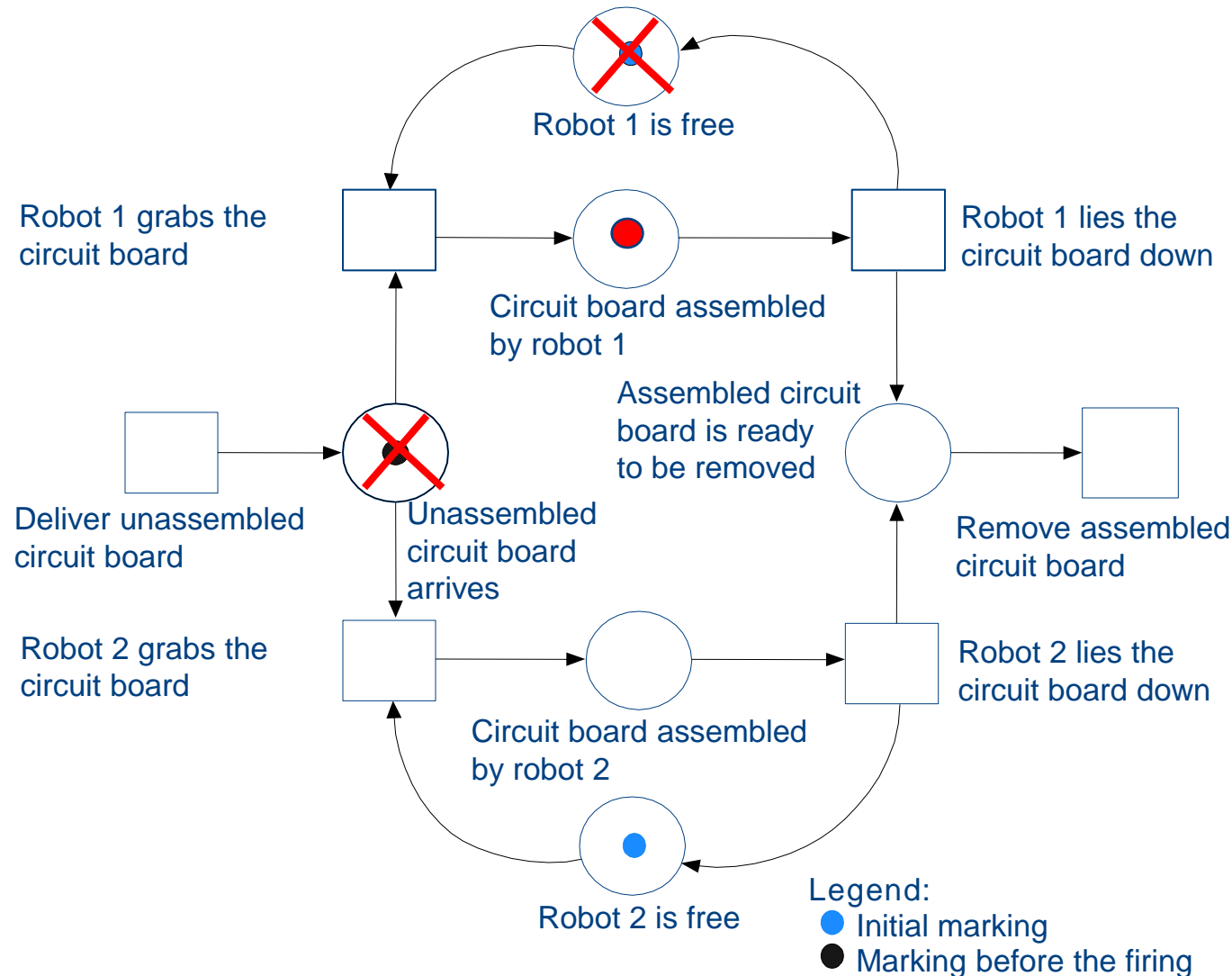
Before the
firing



Petri Nets - Condition / Event Petri Nets

Condition/Event Net: Example

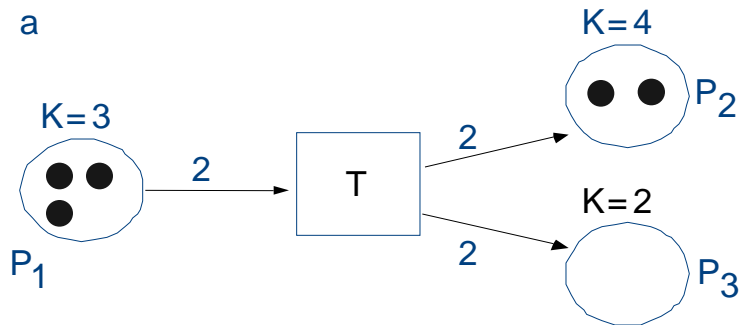
- C/E Net of the assembling robot



After the
firing

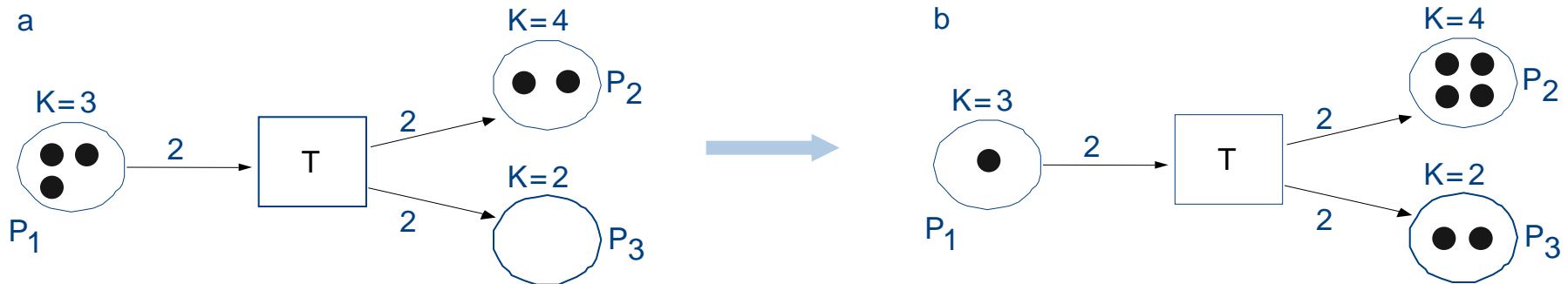
- **P/T Nets** (*P/T Net, Place/Transition Net*)
 - Places can obtain **more than one** token (in C/E nets only one token)
 - Transitions must release or add as many tokens when firing as the **weights** that are given on the arrows. (in C/E nets only one token)
 - If the capacity of a place is to be bigger than 1, this will be denoted as »**K** = ...« at the place.
 - The capacity defines the maximum number of tokens that may lie in one place.

- Firing with P/T Nets



- Before the firing
 - P_1 : 3 Tokens
 - P_2 : 2 Tokens
 - in P_3 : no Token.

- Firing with P/T Nets



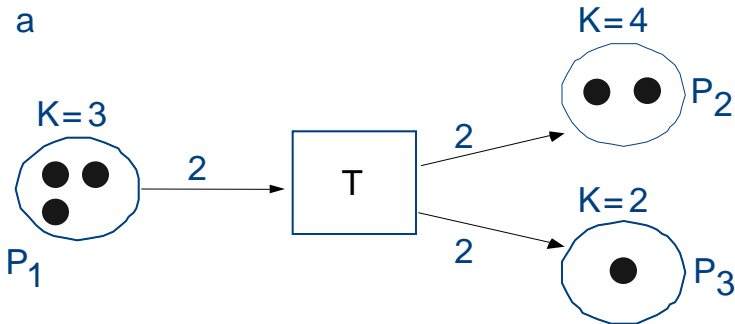
- Before the firing

- P_1 : 3 Tokens
- P_2 : 2 Tokens
- in P_3 : no Token.

- After the firing

- P_1 : 1 Token
- P_2 : 4 Tokens
- in P_3 : 2 Tokens.

- Firing conditions in P/T Nets

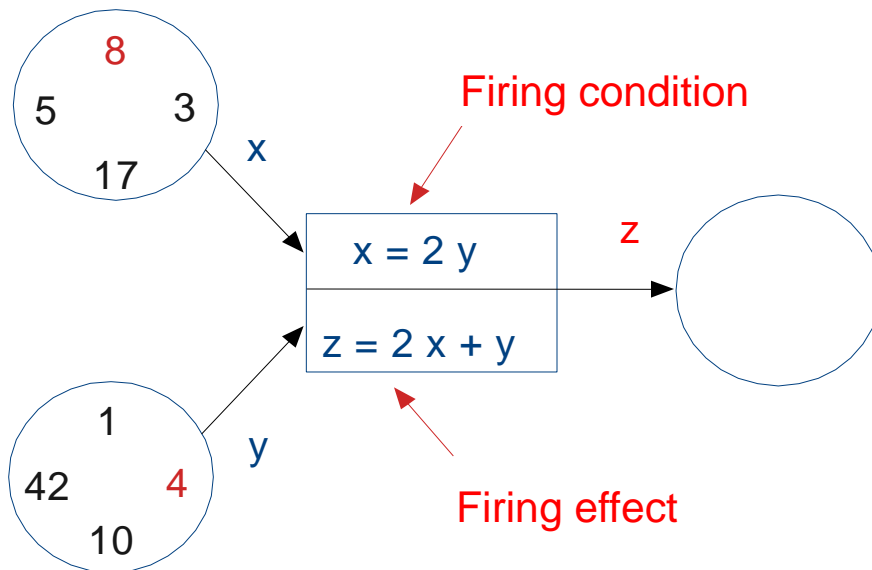


- ◆ T cannot fire because 3 Tokens would then lay in P_3
 - This is not allowed due to $K = 2$ of P_3 .

- Pr/T Nets

- Apply **individual**, »colored« tokens
- C/E and P/T Nets apply only »**black**« tokens, which are all the same

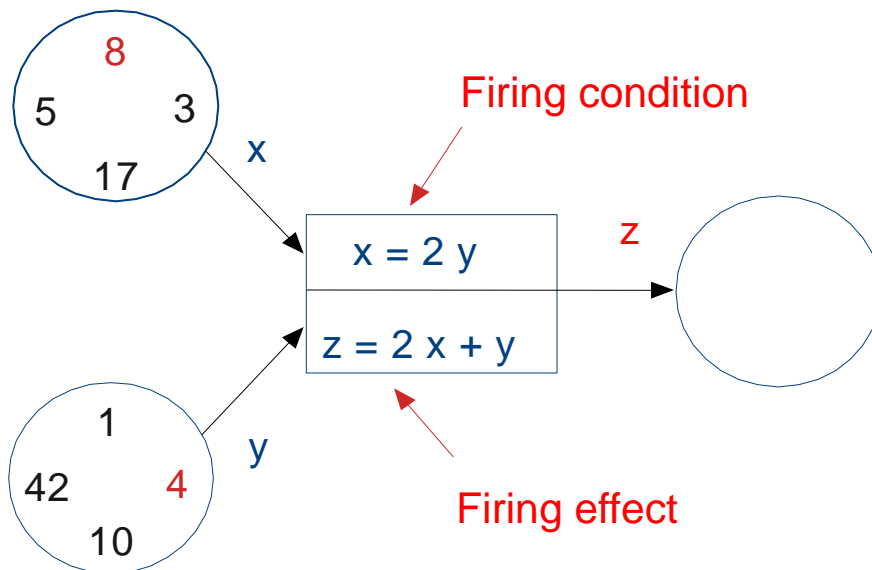
a before



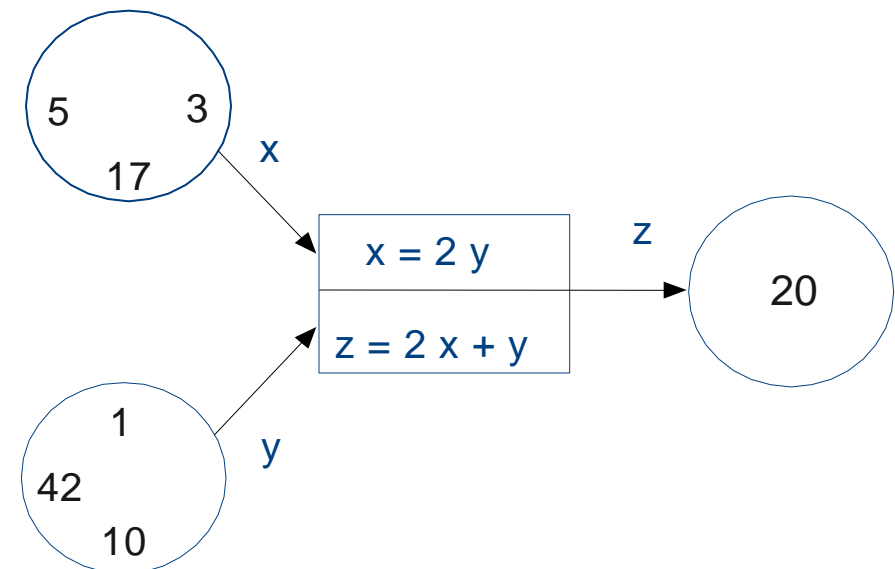
- **Pr/T Nets**

- Use **individual, »colored«** tokens
- C/E and P/T Nets use only **»black«** tokens, which are all the same

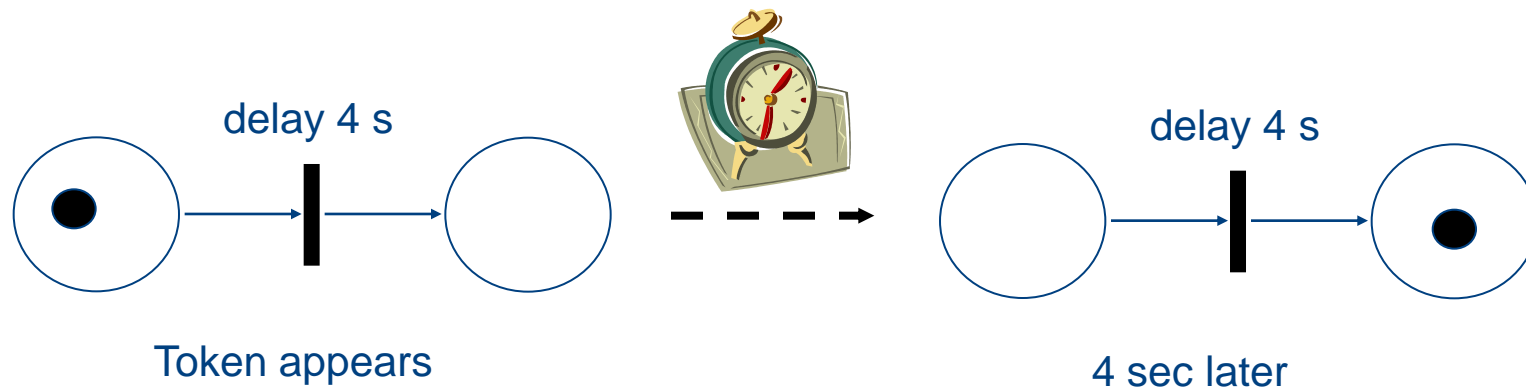
a before



b after



- To study performance and dependability issues of systems it is necessary to include a timing concept into the model.
- There are several possibilities to do this for a Petri net; however, the most common way is to associate a *firing delay* with each transition. This delay specifies the time that the transition has to be *enabled*, before it can actually fire:



SPN (Stochastic Petri Net)

- If the delay is a random distribution function (exponential distribution), the resulting net class is called *stochastic Petri net*.

GSPN (Generalised stochastic Petri Net)

- SPN plus *immediate transitions* (no delay) and inhibit edges.

DSPN

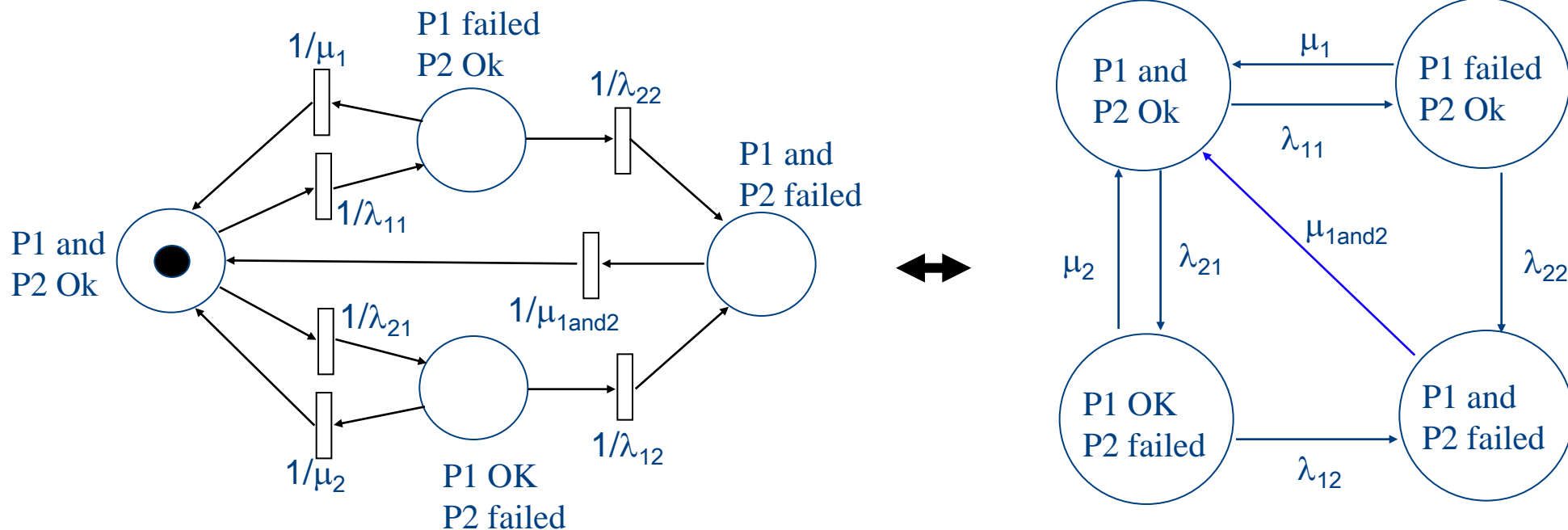
- GSPN plus *deterministic transitions* (delay is fixed).

Petri Nets

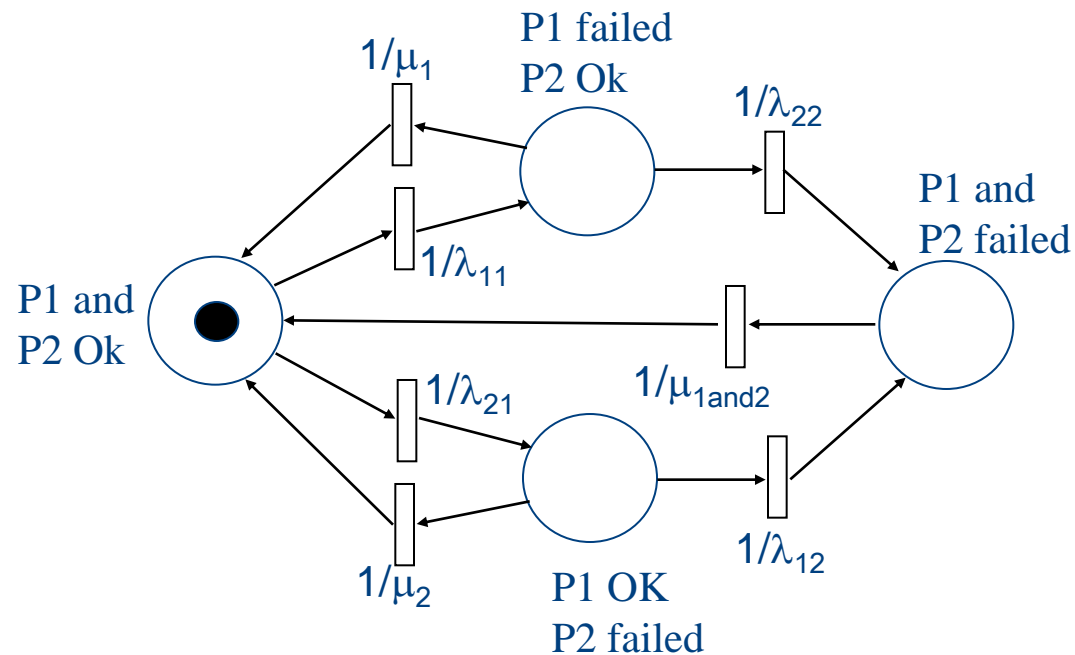
Timed Petri Net Types (SPN)

SPN (Stochastic Petri Net)

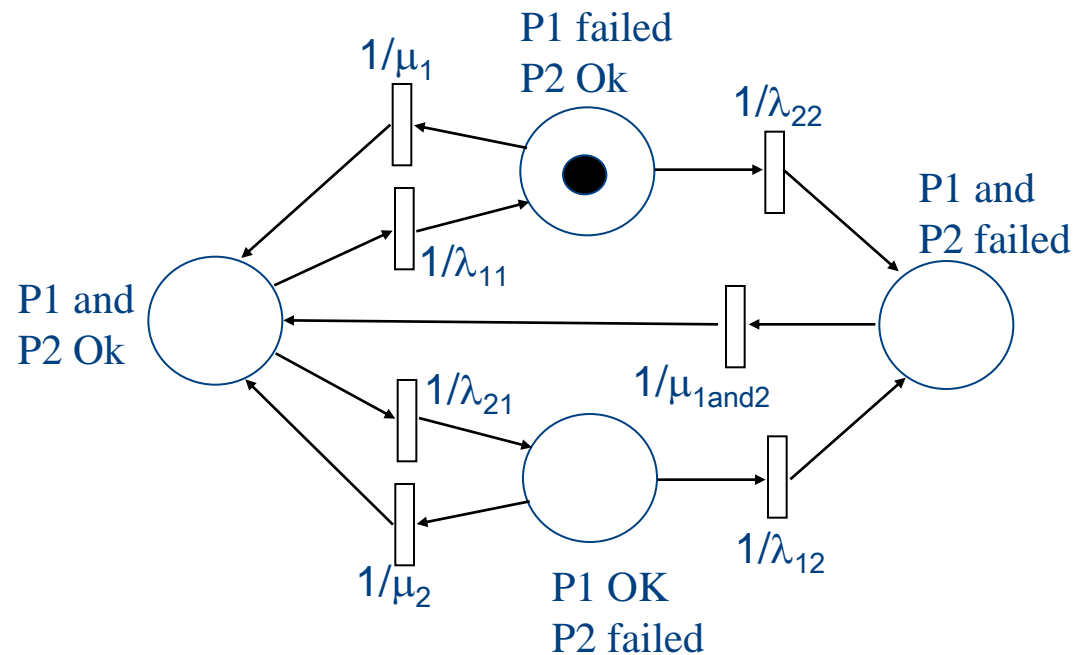
- Delay is exponentially distributed
- Can be transformed into an equivalent Markov Process



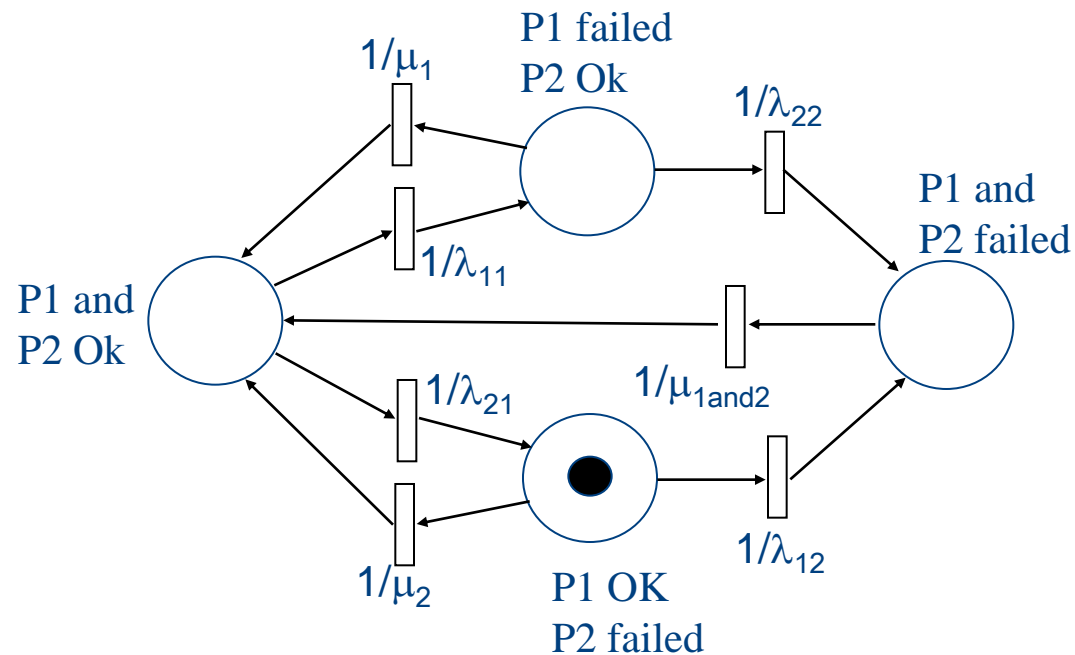
Possible markings: Initial



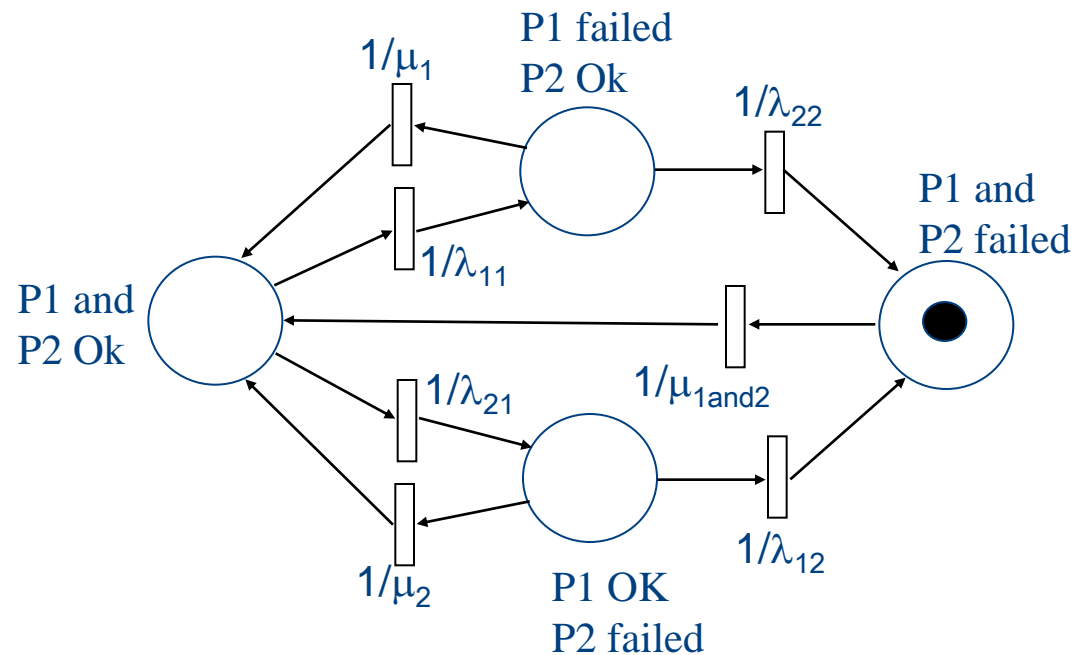
Possible markings: P1 failed



Possible markings: P2 failed

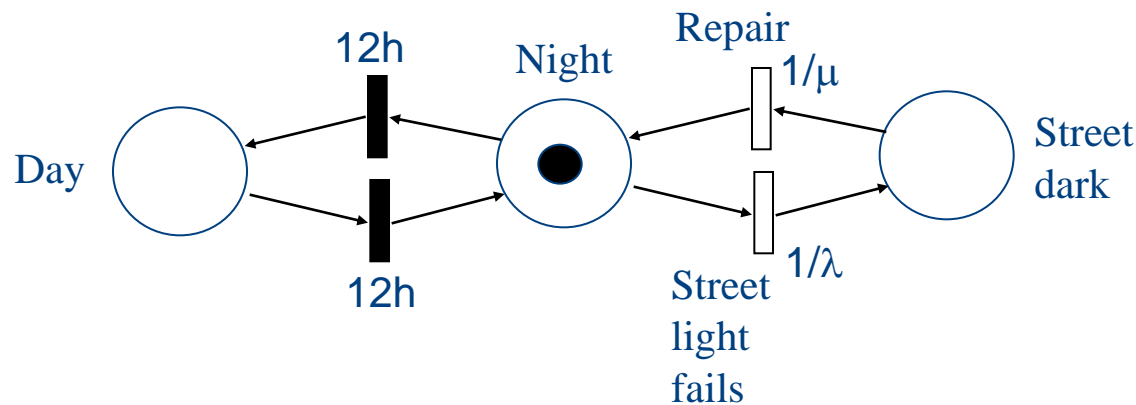


Possible markings: Both failed



DSPN (Deterministic Stochastic Petri Net)

- Exponentially distributed delay + *immediate transitions* (no delay) + *deterministic transitions* (delay is fixed) and inhibit arcs



- Liggesmeyer 2000, Qualitätssicherung softwareintensiver technischer Systeme, Heidelberg: Spektrum-Verlag 2000
- DIN 25424; DIN 25424-1, Fehlerbaumanalyse Methoden und Bildzeichen, September 1981; DIN 25424-2: Fehlerbaumanalyse Handrechenverfahren zur Auswertung eines Fehlerbaumes, April 1990; Berlin: Beuth Verlag
- DIN 25448, Ausfalleffektanalyse (Fehler-Möglichkeits- und -Einfluß-Analyse), Berlin: Beuth Verlag, Mai 1990
- IEC 812, Analysis Techniques for System Reliability - Procedure for Failure Mode and Effect Analysis (FMEA), International Electrotechnical Commission 1985
- IEC 61025, Fault tree analysis (FTA), International Electrotechnical Commission 1990
- IEC 61078, Analysis techniques for dependability - Reliability block diagram method, International Electrotechnical Commission 1991
- IEC 61165, Application of Markov techniques, International Electrotechnical Commission 1995